Fault Tolerant Computing
CS 530
Test Coverage & Defects

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Test Coverage Measures

- Statement or Block coverage
- Branch or decision coverage
- P-use coverage: p-use pair: variable defined/modified - use as predicate
- C-use coverage: similar -use for computation
- Subsumption hierarchy:
  - Covering all branches cover all statements
  - Covering all p-uses cover all branches
Coverage Based Defect Estimation

- Coverage is an objective measure of testing
  - Directly related to test effectiveness
  - Independent of processor speed and testing efficiency
- Lower defect density requires higher coverage to find more faults
- Once we start finding faults, expect coverage vs. defect growth to be linear

Malaiya, Li, Bieman, Karcich, Skibbe, 1994
Li, Malaiya, Denton, 1998
Logarithmic-Exponential Coverage Model

- Hypothesis 1: defect coverage growth follows logarithmic model

\[ C^0(t) = \frac{\beta^0}{N^0} \ln(1 + \beta^0 t), \quad C^0(t) \leq 1 \]

- Hypothesis 2: test coverage growth follows logarithmic model

\[ C^i(t) = \frac{\beta^i}{N^i} \ln(1 + \beta^i t), \quad C^i(t) \leq 1 \]

Log-Expo Coverage Model (2)

- Eliminating t and rearranging,

\[ C^0 = a_0^i \ln[1 + a_1^i (\exp(a_2^i C^i) - 1)], \quad C^0 \leq 1 \]

where \( C^0 \): defect coverage, \( C^i \): test coverage
\( a_0^i, a_1^i, a_2^i \): parameters; \( i \): branch cov, p - use cov etc.

- For “large” Ci, we can approximate

\[ C^0 = -A^i + B^i C^i \]
Coverage Model, Estimated Defects

\[ C^0 = -A^i + B^i C^i, \quad C^i > C^i_{knee} \]

- Only applicable after the knee
- Assumptions: Stable Software

Location of the knee

\[ C_{knee} = 1 - \left( \frac{E_{min}}{D_{min} E_0} \right) D_0 \]

- Based on interpretation through logarithmic model
- Location of knee based on initial defect density
- Lower defect densities cause knee to occur at higher coverage
- Parameter estimation: Malaiya and Denton (HASE '98)
Data Sets Used

Vouk and Pasquini

- Vouk data
  - from N version programming project to create a flight controller
  - Three data sets, 6 to 9 errors each
- Pasquini data
  - Data from European Space Agency
  - C Program with 100,000 source lines
  - 29 of 33 known faults uncovered

Defects vs. Branch Coverage

Data Set: Pasquini

- Defects Expected
- Fitted Model
Estimation of Defect Density

- Estimated defects at 95% coverage, for Pasquini data (assume 5% dead code)
- 28 faults found, and 33 known to exist

<table>
<thead>
<tr>
<th>Measure</th>
<th>Coverage Achieved</th>
<th>Expected Defects</th>
</tr>
</thead>
<tbody>
<tr>
<td>Block</td>
<td>82%</td>
<td>36</td>
</tr>
<tr>
<td>Branch</td>
<td>70%</td>
<td>44</td>
</tr>
<tr>
<td>P-uses</td>
<td>67%</td>
<td>48</td>
</tr>
</tbody>
</table>
Defects vs. P-Use Coverage

Data Set: Vouk 3

Defects Expected

Fitted Model

Coverage Based Estimation

Data Set: Pasquini et al

Estimates are stable
Current Methods

- Development process based models allow for *a priori* estimates
  - Not as accurate as methods based on test data
- Sampling methods often assume faults found as easy to find as faults not found
  - Underestimates faults
- Exponential model
  - Assume applicability of exponential model
  - We present results of a comparison

The Exponential Model

Data Set: Pasquini et al

Estimate rises as new defects found

Estimates very close to actual faults
Related articles

- Frankl & Iakouneno, Proc. SIGSOFT ’98
  - 8 versions of European Space Agency program, 10K LOC, Single fault reinsertion
- Tom Williams, manuscript 1999
  - analysis from first principles
- Peter G Bishop, SAFECOMP 2002
  - A related model, unreachable code

Observations and Conclusions

- Estimates with new method are very stable
  - Visual confirmation of earlier projections
- Which coverage measure to use?
  - Stricter measure will yield closer estimate
- Some code may be dead or unreachable
  - Found with compile or link time tools
  - May need to be taken into account